


<b>Search Notes</b> 	<b>Application/Control No.</b> 10672010	<b>Applicant(s)/Patent Under Reexamination</b> SHIBUYA ET AL.
	<b>Examiner</b> ALEX LIEW	<b>Art Unit</b> 2624

### SEARCHED

Class	Subclass	Date	Examiner
382	141-152	5/31/10	AL
382	181-231	5/31/10	AL

### SEARCH NOTES

Search Notes	Date	Examiner
382/141-152, 181-231 limited to text search	1/1/09	AL
382/141-152, 181-231 limited to text search	8/16/09	AL
382/141-152, 181-231 limited to text search	12/28/09	AL
Consulted with John Strege, concluded that claims 5 and 6 are allowable subject matter, and if included into independent claims 1, 7, 12 and 14, claims can be allowed	5/26/10	AL
382/141-152, 181-231 limited to text search	5/31/10	AL
EAST keyword search, (recogni\$4 identifi\$7 classi\$7) near2 (defect error) near2 distribution same inspect\$4 same wafer	5/31/10	AL
Allowance of claims 10 and 11 were approved by John Strege on 12/28/09	5/31/10	AL
Inventor name search	5/31/10	AL

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	ALL	5/31/10	AL

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